

Notice of References Cited	Application/Control No. 10/527,820		Applicant(s)/Patent Under Reexamination TAKAGI ET AL.	
	Examiner David García Cervetti		Art Unit 2436	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,161,184 A	12-2000	Niimura, Takashi	726/33
*	B	US-2003/0033537 A1	02-2003	Fujimoto et al.	713/193
*	C	US-2003/0065933 A1	04-2003	Hashimoto et al.	713/194
*	D	US-2004/0093505 A1	05-2004	Hatakeyama et al.	713/189
*	E	US-2004/0139341 A1	07-2004	Yamaguchi et al.	713/194
*	F	US-2005/0144438 A1	06-2005	Hashimoto et al.	713/155
*	G	US-2006/0106836 A1	05-2006	Masugi et al.	707/101
*	H	US-2007/0101143 A1	05-2007	Iwata et al.	713/172
*	I	US-2007/0226412 A1	09-2007	Morino et al.	711/113
*	J	US-7,299,363 B2	11-2007	Yamaguchi et al.	713/189
*	K	US-2008/0098239 A1	04-2008	WADA et al.	713/193
*	L	US-7,424,622 B2	09-2008	Hashimoto et al.	713/194
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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